

Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination
				09/661,223	KAIBUKI, FUTOSHI
Examiner				Art Unit	
Kim T. Huynh				2112	

ISSUE CLASSIFICATION					
ORIGINAL			CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
710	305	710	306		
INTERNATIONAL CLASSIFICATION					
G	0	6	F	13/14	
				/	
				/	
				/	
				/	
 Kim T. Huynh 1/10/06 (Assistant Examiner) (Date)			 REHANA PERVEEN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date)  1/11/06		
Total Claims Allowed: 14					
			O.G. Print Claim(s)	O.G. Print Fig.	
			1	1	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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1	5		35	64	95	125	154
1	6		36	65	96	126	155
1	7		37	66	97	127	156
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3	9		39	68	99	129	158
4	10		40	69	100	130	159
5	11		41	70	101	131	160
6	12		42	71	102	132	161
7	13		43	72	103	133	162
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8	17		47	76	107	137	166
9	18		48	77	108	138	167
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